

# Specification for Approval

Date: 2011/9/7

Customer:

TAI-TECH P/N: HCB2012KF-201T20

CUSTOMER P/N:

QUANTITY: pcs

**DESCRIPTION:** 

REMARK:		
Cu	stomer Approval Feedba	ack

西北臺慶科技股份有限公司 TAI-TECH Advanced Electronics Co., Ltd

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# **High Current Ferrite Chip Bead(Lead Free)**

HCB2012KF-201T20

## 1.Features

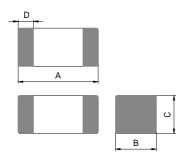
- 1. Monolithic inorganic material construction.
- 2. Closed magnetic circuit avoids crosstalk.
- 3. Suitable for reflow soldering.
- 4. Shapes and dimensions follow E.I.A. spec.
- 5. Available in various sizes.
- 6. Excellent solder ability and heat resistance.
- 7. High reliability.
- 8. 100% Lead(Pb) & Halogen-Free and RoHS compliant.
- 9. Low DC resistance structure of electrode to prevent wasteful electric power consumption.







## 2.Dimensions



Chip Size					
Α	2.00±0.20				
В	1.25±0.20				
С	0.85±0.20				
D	0.50±0.30				

Units: mm

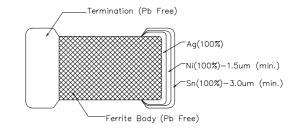
## 3.Part Numbering



D: Impedance 201:

E: Packaging T=Taping and Reel, B=Bulk(Bags)

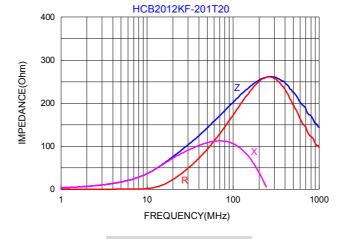
F: Rated Current 20=2000m



## 4. Specification

Tai-Tech Part Number	Impedance ( )	Test Frequency (Hz)	DC Resistance ( ) max.	Rated Current (mA) max.	
HCB2012KF-201T20	200±25%	60mV/100M	0.10	2000	

### ■ Impedance-Frequency Characteristics



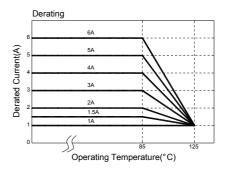
## 5. Reliability and Test Condition

Item					Perfor	mance					Test Condition			
Series No.	FCB	FCM	НСВ	GHB	FCA	FCI	FHI	FCH	HCI	MGI				
Operating Temperature	(In		40~+125 self-temp		rise)	(In		40~+10 self-tem	5 perature	rise)				
Transportation Storage Temperature		-40~+125 -40~+105									Long storage conditions, please see the Application Notice			
Impedance (Z)											Agilent4291			
Inductance (Ls)											Agilent E4991			
Q Factor	Refer	Refer to standard electrical characteristics list									Agilent4287 Agilent16192			
DC Resistance											Agilent 4338			
Rated Current											DC Power Supply Over Rated Current requirements, there will be some risk			
Temperature Rise Test			A ΔT 20 1A ΔT 40								Applied the allowed DC current.     Temperature measured by digital surface thermometer.			
Solder heat Resistance	Imped	lance cha	lo signific ange: Wit ange: : wi	hin ± 30	%.			damage. ninal elec	trode:75%	6 min.	Preheat: 150 ,60sec. Solder: Sn-Cu0.5 Solder tamperature: 260±5 Flux for lead free: ROL0 Dip time: 10±0.5sec.  Preheating Dipping Natural cooling 260°C  150°C  60  10±0.5 second			
Solderability		ode sho	% of the buld be			245° C	Preheating Dip	ping Natural	.1		Preheat: 150 ,60sec. Solder: Sn-Cu0.5 Solder tamperature: 245±5 Flux for lead free: ROL0 Dip time: 4±1sec.			
Terminal strength	not be	The terminal electrode and the dielectric must not be damaged by the forces applied on the right conditions.						N	For FCB FCM HCB GHB FCI FHI FCH HCI MGI: Size Force (Kgf) Time(sec) 1005 0.2 1608 0.5 2012 0.6 3216 1.0 >30 3225 1.0 4516 1.0 4532 1.5  For FCA: Size Force (Kgf) Time(sec) 3216 0.5 >30					
Flexture strength	not be		electrode ed by the				-	5(1.772) 45(		Solder a chip on a test substrate, bend t substrate by 2mm (0.079in)and return.  The duration of the applied forces shall be (+ 5) Sec.				
Bending Strength			ould not			<u>R 0</u>	.5(0.02	1.0(0.039 2) — Chip	9)		Size         mm(inches)         P-Kgf           1608         0.80(0.033)         0.3           2012         1.40(0.055)         1.0           FCA3216         2.00(0.079)         1.5           3216         3.225         2.00(0.079)         2.5           4516         4532         2.70(0.106)         2.5			
Random Vibration Test	Appearance: Cracking, shipping and any other defects harmful to the characteristics should not be allowed.  Impedance: within±30%  Inductance change: : within±10%.								Frequency: 10-55-10Hz for 15 min. Amplitude: 1.52mm Directions and times: X, Y, Z directions for 15 min This cycle shall be performed 12 times in each of three mutually perpendicular directions (Total 9hours).					

Item	Perfor		Test Condition		
Life testing at High Temperature	Appearance: no damage.				Temperature: 125±2 (bead), 105±2 (inductor) Applied current: rated current. Duration: 1008±12hrs. Measured at room temperature after placing for 2 to 3hrs.
Humidity	Inductance: within±10%of initial value. Q: within±30%of initial value. (FCI FHI Q: within±20%of initial value. (HCI MG	Humidity: 90~95%RH. Temperature: 40±2 . Temperature: 60±2 .(HCI MGI) Duration: 504±8hrs. Measured at room temperature after plac for 2 to 3hrs.			
Thermal shock	Appearance: no damage.  Impedance: within±30%of initial value. Inductance: within±10%of initial value. Q: within±30%of initial value.	Phase Temper  1	±2 i temp. 5±2	Time(min.) 30±5 0.5 30±5	Condition for 1 cycle Step1: -40±2 30±5 min. Step2: +105±2 30±5min. Number of cycles: 500 Measured at room temperature after placing for 2 to 3 hrs.
Low temperature storage test	(FCI FHI FCH) Q: within±20%of initial value. (HCI MGI)		Temperature: -40±2 . Duration: 500±8hrs. Measured at room temperature after placing for 2 to 3hrs.		
Drop	No mechanical damage Impedance change: ±30% Inductance change: : within±10%				Drop 10 times on a concrete floor from a height of 75cm

## \*\*Derating Curve

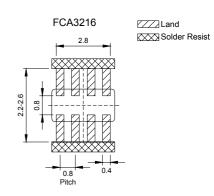
For the ferrite chip bead which withstanding current over 1.5A, as the operating temperature over 85 , the derating current information is necessary to consider with. For the detail derating of current, please refer to the Derated Current vs. Operating Temperature curve.

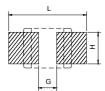


## 6. Soldering and Mounting

## 6-1. Recommended PC Board Pattern

		Land Patterns For Reflow Soldering						
Series	Туре	A(mm)	B(mm)	C(mm)	D(mm)	L(mm)	G(mm)	H(mm)
FCB	0603	0.6±0.03	0.30±0.03	0.30±0.03	0.15±0.05	0.80	0.30	0.30
FCM	1005	1.0±0.10	0.50±0.10	0.50±0.10	0.25±0.10	1.50	0.40	0.55
нсв	1608	1.6±0.15	0.80±0.15	0.80±0.15	0.30±0.20	2.60	0.60	0.80
GHB	2012	2.0±0.20	1.25±0.20	0.85±0.20	0.50±0.30	3.00	1.00	1.00
FCI	2012	2.0±0.20	1.25±0.20	1.25±0.20	0.50±0.30	3.00		
FHI	3216	3.2±0.20	1.60±0.20	1.10±0.20	0.50±0.30	4.40	2.20	1.40
FCH	3225	3.2±0.20	2.50±0.20	1.30±0.20	0.50±0.30	4.40	2.20	3.40
HCI	4516	4.5±0.20	1.60±0.20	1.60±0.20	0.50±0.30	5.70	2.70	1.40
MGI	4532	4.5±0.20	3.20±0.20	1.50±0.20	0.50±0.30	5.90	2.57	4.22





PC board should be designed so that products are not sufficient under mechanical stress as warping the board.

Products shall be positioned in the sideway direction against the mechanical stress to prevent failure.

### 6-2. Soldering

Mildly activated rosin fluxes are preferred. The minimum amount of solder can lead to damage from the stresses caused by the difference in coefficients of expansion between solder, chip and substrate. The terminations are suitable for re-flow soldering systems. If hand soldering cannot be avoided, the preferred technique is the utilization of hot air soldering tools.

If Use Wave soldering is there will be some risk.

Re-flow soldering temperatures below 240 degrees, there will be unwitting risk

#### 6-2.1 Lead Free Solder re-flow:

Recommended temperature profiles for lead free re-flow soldering in Figure 1.

#### 6-2.2 Soldering Iron:

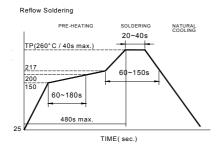
Products attachment with a soldering iron is discouraged due to the inherent process control limitations. In the event that a soldering iron must be employed the following precautions are recommended. for Iron Soldering in Figure 2.

Preheat circuit and products to 150 350 tip temperature (max)

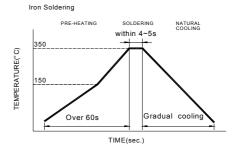
Never contact the ceramic with the iron tip 1.0mm tip diameter (max)

Use a 20 watt soldering iron with tip diameter of 1.0mm

Limit soldering time to 4~5sec.



Reflow times: 3 times max Fig.1



Iron Soldering times: 1 times max Fig.2

#### 6-2.3 Solder Volume:

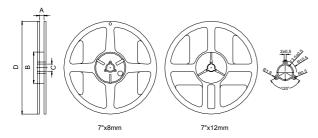
Accordingly increasing the solder volume, the mechanical stress to product is also increased. Exceeding solder volume may cause the failure of mechanical or electrical performance. Solder shall be used not to be exceed as shown in right side:

Minimum fillet height = soldering thickness + 25% product height



## 7. Packaging Information

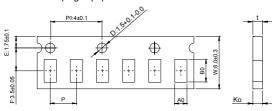
### 7-1. Reel Dimension



Туре	A(mm)	B(mm)	C(mm)	D(mm)	
7"x8mm	9.0±0.5	60±2	13.5±0.5	178±2	
7"x12mm	13.5±0.5	60±2	13.5±0.5	178±2	

### 7-2.1 Tape Dimension / 8mm

Material of taping is paper

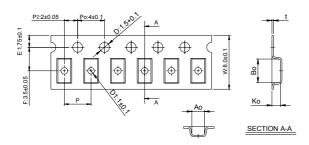


E:1.75±0.1	P22±0.1 P0.4±0.1 St.45.00 M.18.5	t
F:3.5±0.1	P A0	Ko

Size	Bo(mm)	Ao(mm)	Ko(mm)	P(mm)	t(mm)	D1(mm)
060303	0.68±0.05	0.38±0.05	0.50max	2.0±0.05	0.50max	none

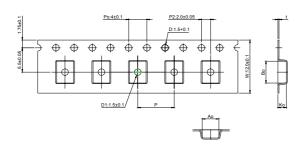
Size	Bo(mm)	Ao(mm)	Ko(mm)	P(mm)	t(mm)	D1(mm)
100505	1.12±0.03	0.62±0.03	0.60±0.03	2.0±0.10	0.60±0.03	none
160808	1.85±0.05	1.05±0.05	0.95±0.05	4.0±0.10	0.95±0.05	none
201209	2.30±0.05	1.50±0.05	0.95±0.05	4.0±0.10	0.95±0.05	none

Material of taping is plastic



Size	Bo(mm)	Ao(mm)	Ko(mm)	P(mm)	t(mm)	D1(mm)
160808	1.95±0.10	1.05±0.10	1.05±0.10	4.0±0.10	0.23±0.05	none
201209	2.25±0.10	1.42±0.10	1.04±0.10	4.0±0.10	0.22±0.05	1.0±0.10
201212	2.35±0.10	1.50±0.10	1.45±0.10	4.0±0.10	0.22±0.05	1.0±0.10
321611	3.50±0.10	1.88±0.10	1.27±0.10	4.0±0.10	0.22±0.05	1.0±0.10
322513	3.42±0.10	2.77±0.10	1.55±0.10	4.0±0.10	0.22±0.05	1.0±0.10
321609	3.40±0.10	1.77±0.10	1.04±0.10	4.0±0.10	0.22±0.05	1.0±0.10

### 7-2.2 Tape Dimension / 12mm

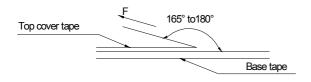


ĺ	Size	Bo(mm)	Ao(mm)	Ko(mm)	P(mm)	t(mm)	D1(mm)
	451616	4.95±0.1	1.93±0.1	1.93±0.1	4.0±0.1	0.24±0.05	1.5±0.1
	453215	4.95±0.1	3.66±0.1	1.85±0.1	8.0±0.1	0.24±0.05	1.5±0.1

### 7-3. Packaging Quantity

Chip Size	453215	451616	322513	321611	321609	201212	201209	160808	100505	060303
Chip / Reel	1000	2000	2500	3000	3000	2000	4000	4000	10000	15000
Inner box	4000	8000	12500	15000	15000	10000	20000	20000	50000	75000
Middle box	20000	40000	62500	75000	75000	50000	100000	100000	250000	375000
Carton	40000	80000	125000	150000	150000	100000	200000	200000	500000	750000
Bulk (Bags)	12000	20000	30000	50000	50000	100000	150000	200000	300000	

### 7-4. Tearing Off Force



The force for tearing off cover tape is 15 to 60 grams in the arrow direction under the following conditions.

Room Temp.	Room Humidity	Room atm	Tearing Speed
( )	(%)	(hPa)	mm/min
5~35	45~85	860~1060	300

## **Application Notice**

### Storage Conditions

To maintain the solderability of terminal electrodes:

- 1. TAI-TECH products meet IPC/JEDEC J-STD-020D standard-MSL, level 1.
- 2. Temperature and humidity conditions: -10~ 40 and 30~70% RH.
- 3. Recommended products should be used within 6 months from the time of delivery.
- 4. The packaging material should be kept where no chlorine or sulfur exists in the air.

#### Transportation

- 1. Products should be handled with care to avoid damage or contamination from perspiration and skin oils.
- 2. The use of tweezers or vacuum pick up is strongly recommended for individual components.
- 3. Bulk handling should ensure that abrasion and mechanical shock are minimized.





# **Test Report**

號碼(No.): CE/2011/41275 日期(Date): 2011/04/15 頁數(Page): 1 of 8

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以下測試樣品係由客户送樣,且由客户聲稱並經客户確認如下 (The following samples was/were submitted and identified by/on behalf of the client as):

樣品名稱(Sample Description)

FERRITE CHIP BEAD INDUCTOR ARRAY MCF MCM YMV SERIES

樣品型號(Style/Item No.)

FERRITE CHIP BEAD INDUCTOR ARRAY MCF MCM YMV SERIES

收件日期(Sample Receiving Date)

2011/04/08

測試期間(Testing Period)

2011/04/08 TO 2011/04/15

測試結果(Test Results)

: 請見下一頁 (Please refer to next pages).



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# **Test Report**

號碼(No.): CE/2011/41275 日期(Date): 2011/04/15 頁數(Page): 2 of 8

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(江蘇省昆山市篷朗昆嘉高科技工業區郭澤路 / GUO-ZE ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA)

#### 測試結果(Test Results)

測試部位(PART NAME) No.1 :

整體混測-八款 (MIXED ALL PARTS-EIGHT KINDS)

測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限値 (MDL)	結果 (Result) No.1
鎬 / Cadmium (Cd)	mg/kg	參考IEC 62321: 2008方法, 以感 應耦合電漿原子發射光譜儀檢測。 / With reference to IEC 62321: 2008 and performed by ICP-AES.	2	n.d.
鉛 / Lead (Pb)	mg/kg	參考IEC 62321: 2008方法, 以感 應耦合電漿原子發射光譜儀檢測 / With reference to IEC 62321: 2008 and performed by ICP-AES.	2	83
汞 / Mercury (Hg)	mg/kg	參考IEC 62321: 2008方法,以感 應耦合電漿原子發射光譜儀檢測. / With reference to IEC 62321: 2008 and performed by ICP-AES.	2	n.d.
六價鉻 / Hexavalent Chromium Cr(VI) by alkaline extraction	mg/kg	參考IEC 62321: 2008方法,以UV- VIS檢測. / With reference to IEC 62321: 2008 and performed by UV-VIS.	2	n.d.

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Test Report

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測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限値 (MDL)	結果 (Result) No.1
多溴聯苯總和 / Sum of PBBs			-	n.d.
一溴聯苯 / Monobromobiphenyl	]		5	n.d.
二溴聯苯 / Dibromobiphenyl			5	n.d.
三溴聯苯 / Tribromobiphenyl			5	n.d.
四溴聯苯 / Tetrabromobiphenyl			5	n.d.
五溴聯苯 / Pentabromobiphenyl			5	n.d.
六溴聯苯 / Hexabromobiphenyl			5	n.d.
七溴聯苯 / Heptabromobiphenyl		冬考IEC 62321: 2008方法,以氣	5	n.d.
八溴聯苯 / Octabromobiphenyl			5	n.d.
九溴聯苯 / Nonabromobiphenyl			5	n.d.
十溴聯苯 / Decabromobiphenyl		相層析儀/質譜儀檢測. / With	5.	n.d.
多溴聯苯醚總和 / Sum of PBDEs	mg/kg	reference to IEC 62321; 2008	_	n.d.
一溴聯苯醚 / Monobromodiphenyl ether		and performed by GC/MS.	5	n.d.
二溴聯苯醚 / Dibromodiphenyl ether			5	n.d.
三溴聯苯醚 / Tribromodiphenyl ether			5	n.d.
四溴聯苯醚 / Tetrabromodiphenyl ether			5	n.d.
五溴聯苯醚 / Pentabromodiphenyl ether			5	n.d.
六溴聯苯醚 / Hexabromodiphenyl ether			5	n.d.
七溴聯苯醚 / Heptabromodiphenyl ether			5	n.d.
八溴聯苯醚 / Octabromodiphenyl ether			5	n.d.
九溴聯苯醚 / Nonabromodiphenyl ether			5	n.d.
十溴聯苯醚 / Decabromodiphenyl ether			5	n.d.

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State advisor Edu. 台灣極級對性股份有限公司 | Chemical-Taipei 33 WuChyuan Road, Wuku Industrial Zone, New Taipei City, Taiwan 新北市五酸工業區五橋橋約縣 + 886 (02)2299 3279 f + 886 (02)2299 3237 www.sgs.com



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測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限値 (MDL)	結果 (Result) No.1
鹵素 / Halogen				
鹵素(氟)/ Halogen-Fluorine (F) (CAS No.: 14762-94-8)		参考BS EN 14582:2007, 以離子層 析儀分析. / With reference to BS EN 14582:2007. Analysis was performed by IC.	50	n.d.
鹵素 (氣) / Halogen-Chlorine (Cl) (CAS No.: 22537-15-1)			50	n.d.
鹵素(溴)/ Halogen-Bromine (Br) (CAS No.: 10097-32-2)	mg/kg		50	n.d.
鹵素(碘)/ Halogen-Iodine (I) (CAS No.: 14362-44-8)			50	n.d.

#### 備註(Note):

- 1. mg/kg = ppm ; 0.1wt% = 1000ppm
- 2. n.d. = Not Detected (未检出)
- 3. MDL = Method Detection Limit (方法偵測極限値)
- 4. "-" = Not Regulated (無規格值)
- 5. 樣品的測試是基於申請人要求混合測試,報告中的混合測試結果不代表其中個别單一材質的含量。 (The samples was/were analyzed on behalf of the applicant as mixing sample in one testing. The above results was/were only given as the informality value.)

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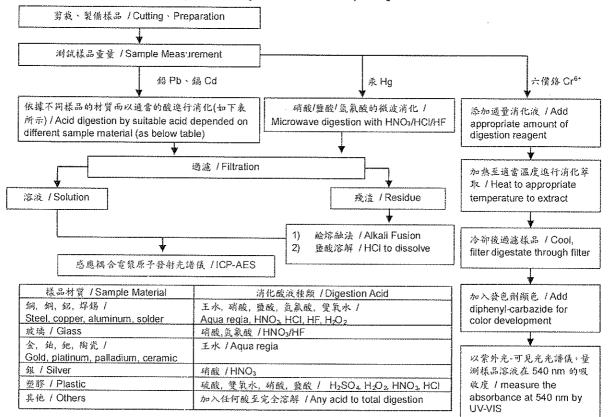
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- 根據以下的流程圖之條件,樣品已完全溶解。(六價鉻測試方法除外) / These samples were dissolved totally by pre-conditioning method according to below flow chart. (Cr<sup>6\*</sup> test method excluded)
- 2) 测試人員:楊登偉 / Name of the person who made measurement: Climbgreat Yang
- 3) 測試負責人:張啓與 / Name of the person in charge of measurement: Troy Chang



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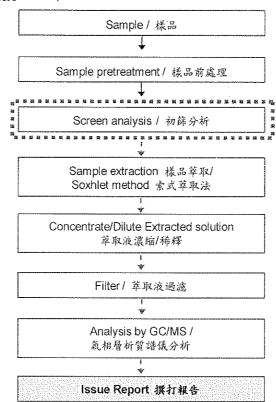
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## 多溴聯苯/多溴聯苯醚分析流程圖 / PBB/PBDE analytical FLOW CHART

- 1) 測試人員: 翁賜彬 / Name of the person who made measurement: Roman Wong

確認程序 / Confirmation process - · - →



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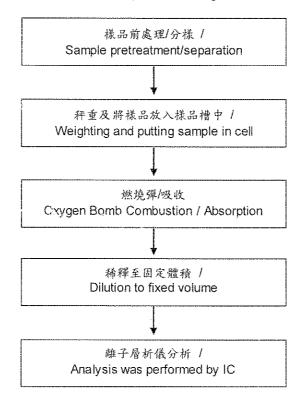
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## 鹵素分析流程圖 / Analytical flow chart of halogen content

- 1) 测試人員: 陳思臻 / Name of the person who made measurement: Rita Chen
- 2) 測試負責人:張啓興 / Name of the person in charge of measurement: Troy Chang



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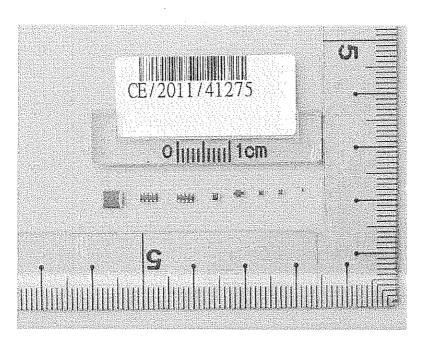
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